

Everett D Grimley

List of Publications by Year in descending order

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29
papers

1,949
citations

687363

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docs citations

29
times ranked

1693
citing authors

#	ARTICLE	IF	CITATIONS
1	Multiple Epsilon-Near-Zero Resonances in Multilayered Cadmium Oxide: Designing Metamaterial-Like Optical Properties in Monolithic Materials. ACS Photonics, 2019, 6, 1139-1145.	6.6	33
2	Transmission Electron Microscopy (STEM and TEM). , 2019, , 317-340.		1
3	Polarization-dependent electric potential distribution across nanoscale ferroelectric Hf _{0.5} Zr _{0.5} O ₂ in functional memory capacitors. Nanoscale, 2019, 11, 19814-19822.	5.6	11
4	Charge confinement and thermal transport processes in modulation-doped epitaxial crystals lacking lattice interfaces. Physical Review Materials, 2019, 3, .	2.4	2
5	Analysis of Performance Instabilities of Hafnia-Based Ferroelectrics Using Modulus Spectroscopy and Thermally Stimulated Depolarization Currents. Advanced Electronic Materials, 2018, 4, 1700547.	5.1	51
6	Atomic Structure of Domain and Interphase Boundaries in Ferroelectric HfO ₂ . Advanced Materials Interfaces, 2018, 5, 1701258.	3.7	114
7	Structure of Ultrathin Native Oxides on III-Nitride Surfaces. ACS Applied Materials & Interfaces, 2018, 10, 10607-10611.	8.0	34
8	Complexities of atomic structure at CdO/MgO and CdO/Al ₂ O ₃ interfaces. Journal of Applied Physics, 2018, 124, .	2.5	2
9	Extracting Thickness and Tilt From 4D-STEM Datasets to Model the Influence on ABF Images. Microscopy and Microanalysis, 2018, 24, 216-217.	0.4	1
10	Insights into Texture and Phase Coexistence in Polycrystalline and Polyphasic Ferroelectric HfO ₂ Thin Films using 4D-STEM. Microscopy and Microanalysis, 2018, 24, 184-185.	0.4	4
11	Si Doped Hafnium Oxide—A “Fragile” Ferroelectric System. Advanced Electronic Materials, 2017, 3, 1700131.	5.1	136
12	An Ultrathin Single Crystalline Relaxor Ferroelectric Integrated on a High Mobility Semiconductor. Nano Letters, 2017, 17, 6248-6257.	9.1	11
13	Structure and Chemistry of Oxide Surface Reconstructions in III-Nitrides Observed using STEM EELS. Microscopy and Microanalysis, 2017, 23, 1444-1445.	0.4	0
14	Compositional Ordering and Polar Nano-Regions: Physical Effects of Sn Alloying in SrTiO ₃ Thin Films. Microscopy and Microanalysis, 2017, 23, 1582-1583.	0.4	0
15	Utilizing High-temperature Atomic-resolution STEM and EELS to Determine Reconstructed Surface Structure of Complex Oxide. Microscopy and Microanalysis, 2017, 23, 1596-1597.	0.4	0
16	In-situ-by-Ex-situ: FIB-less Preparation of Bulk Samples on Heating Membranes for Atomic Resolution STEM Imaging. Microscopy and Microanalysis, 2016, 22, 774-775.	0.4	1
17	Physical Mechanisms behind the Field-Cycling Behavior of HfO ₂ -Based Ferroelectric Capacitors. Advanced Functional Materials, 2016, 26, 4601-4612.	14.9	586
18	Observing Misfit Dislocation Interactions Across Thin Film Oxide Heterostructures. Microscopy and Microanalysis, 2016, 22, 1506-1507.	0.4	0

#	ARTICLE	IF	CITATIONS
19	In-situ real-space imaging of single crystal surface reconstructions via electron microscopy. Applied Physics Letters, 2016, 109, 201601.	3.3	17
20	Unleashing Strain Induced Ferroelectricity in Complex Oxide Thin Films via Precise Stoichiometry Control. Advanced Functional Materials, 2016, 26, 7271-7279.	14.9	30
21	Structural Changes Underlying Field-Driven Cycling Phenomena in Ferroelectric HfO ₂ Thin Films. Advanced Electronic Materials, 2016, 2, 1600173.	5.1	301
22	Growth of SrVO ₃ thin films by hybrid molecular beam epitaxy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2015, 33, .	2.1	22
23	Origin of Ferroelectricity in Thin Film HfO ₂ Probed by Revolving STEM and PACBED. Microscopy and Microanalysis, 2015, 21, 779-780.	0.4	2
24	Revealing Unit Cell Level Distortions in Random Oxide Solid Solutions by Scanning Transmission Electron Microscopy and the Projected Pair Distribution Function. Microscopy and Microanalysis, 2015, 21, 1239-1240.	0.4	0
25	Direct observation of charge mediated lattice distortions in complex oxide solid solutions. Applied Physics Letters, 2015, 106, .	3.3	33
26	On the structural origins of ferroelectricity in HfO ₂ thin films. Applied Physics Letters, 2015, 106, .	3.3	447
27	Ferroelectric phenomena in Si-doped HfO ₂ thin films with TiN and Ir electrodes. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2014, 32, .	1.2	110
28	Application of the Projective Standard Deviation to STEM Imaging and Analysis. Microscopy and Microanalysis, 2014, 20, 118-119.	0.4	0
29	Putting a New Spin on Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2014, 20, 140-141.	0.4	0